



# 150V,84A, 8.1m N-channel Power SGT MOSFET

## JMSH1509PC

### Features

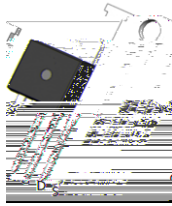
- Excellent  $R_{DS(ON)}$  and Low Gate Charge
- 100% UIS Tested
- 100% Vds Tested
- Halogen-free; RoHS-compliant

### Applications

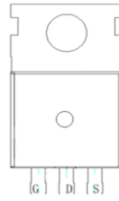
- Load Switch
- PWM Application
- Power Management

### Product Summary

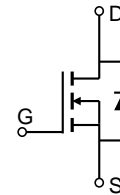
Parameters	Value	Unit
$V_{DSS}$	150	V
$V_{GS(th\_Typ)}$	3.2	V
$I_D(@V_{GS}=10V)$	84	A
$R_{DS(ON)\_Typ}(@V_{GS}=10V)$	8.1	m $\Omega$



TO-220-3L Top View



Pin Assignment



Schematic Diagram

### Ordering Information

Device	Marking	MSL	Form	Package	Tube(pcs)	Per Carton (pcs)
JMSH1509PC-U	SH1509P	N/A	Tube	TO-220-3L	50	5000

### Absolute Maximum Ratings (@ $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-to-Source Voltage	150	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ\text{C}$	84
		$T_C = 100^\circ\text{C}$	59
$I_{DM}$	Pulsed Drain Current <sup>(1)</sup>	Refer to Fig.4	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>(2)</sup>	389	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ\text{C}$	170
		$T_C = 100^\circ\text{C}$	68
$T_J, T_{STG}$	Junction & Storage Temperature Range	-55 to 150	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	Max	Unit
R	Thermal Resistance, Junction to Ambient <sup>(3)</sup>	28	$^\circ\text{C/W}$
R	Thermal Resistance, Junction to Case	0.7	



**Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$	150	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 120\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1.0	$\mu\text{A}$
$I_{GSS}$	Gate-Body Leakage Current	$V_{DS} = 0\text{V}$ , $V_{GS} = \pm 20\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$	2.2	3.2	4.1	V
$R_{DS(ON)}$	Static Drain-Source ON-Resistance <sup>(4)</sup>	$V_{GS} = 10\text{V}$ , $I_D = 20\text{A}$	-	8.1	10.6	m $\Omega$
<b>Dynamic Characteristics</b>						
$R_g$	Gate Resistance	$f = 1\text{MHz}$	-	3.7	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS} = 0\text{V}$ , $V_{DS} = 75\text{V}$ , $f = 1\text{MHz}$	-	3569	5353	pF
$C_{oss}$	Output Capacitance		-	323	485	pF
$C_{riss}$	Reverse Transfer Capacitance		-	14	21	pF
$Q_g$	Total Gate Charge	$V_{GS} = 0$ to $10\text{V}$ $V_{DS} = 75\text{V}$ , $I_D = 20\text{A}$	-	53	-	nC
$Q_{gs}$	Gate Source Charge		-	19	-	nC
$Q_{gd}$	Gate Drain ("Miller") Charge		-	12	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = 10\text{V}$ , $V_{DD} = 75\text{V}$ $I_D = 20\text{A}$ , $R_{GEN} = 3\Omega$	-	16	-	ns
$t_r$	Turn-On Rise Time		-	29	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	39	-	ns
$t_f$	Turn-Off Fall Time		-	16	-	ns
<b>Body Diode Characteristics</b>						
$I_S$	Maximum Continuous Body Diode Forward Current		-	-	84	A
$I_{SM}$	Maximum Pulsed Body Diode Forward Current		-	-	336	A
$V_{SD}$	Body Diode Forward Voltage	$V_{GS} = 0\text{V}$ , $I_S = 20\text{A}$	-		1.2	V
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F = 15\text{A}$ , $di/dt = 100\text{A}/\mu\text{s}$	-	85	-	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge		-	253	-	nC

- Notes:
1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
  2.  $E_{AS}$  condition: Starting  $T_J = 25^\circ\text{C}$ ,  $V_{DD} = 75\text{V}$ ,  $V_G = 10\text{V}$ ,  $R_G = 25\text{ohm}$ ,  $L = 3\text{mH}$ ,  $I_{AS} = 16.1\text{A}$ ,  $V_{DD} = 0\text{V}$  during time in avalanche.
  3. R is measured with the device mounted on a 1inch<sup>2</sup> pad of 2oz copper FR4 PCB.
  4. Pulse Test: Pulse Width 0.5%.





### Typical Performance Characteristics

Figure 1: Power De-rating

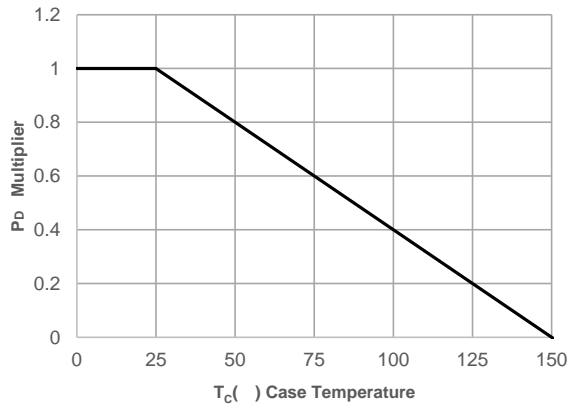
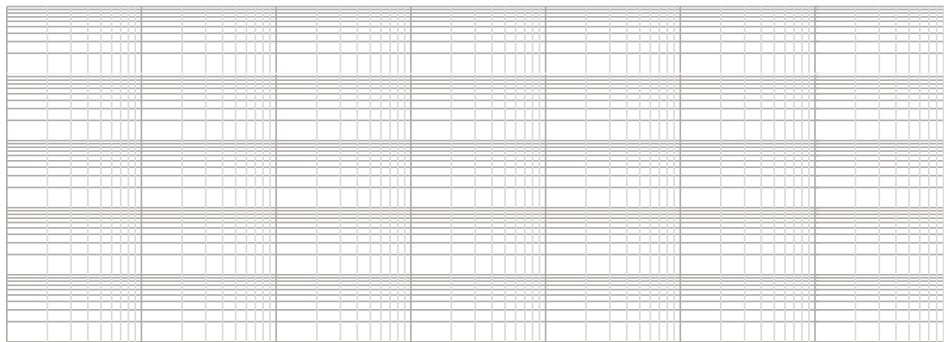
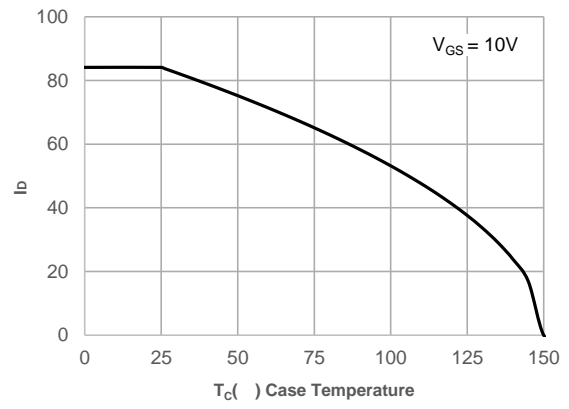


Figure 2: Current De-rating







### Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

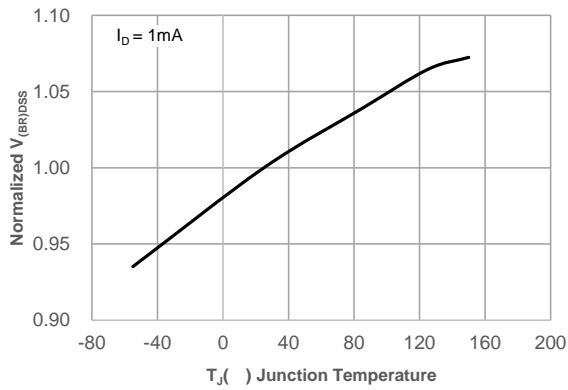


Figure 12: Normalized on Resistance vs. Junction Temperature

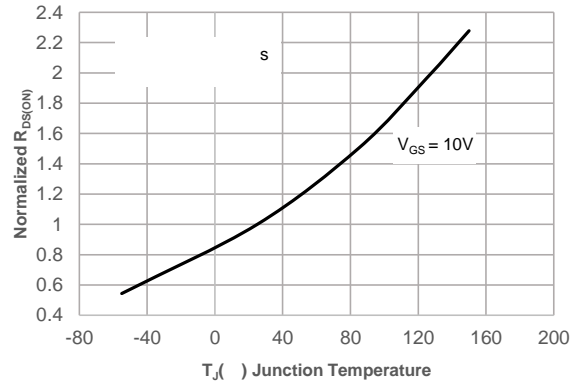


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

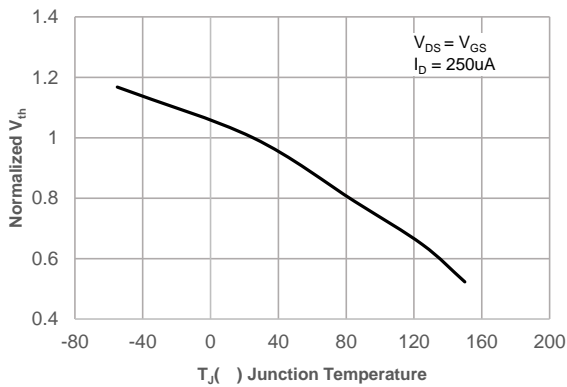


Figure 14:  $R_{DS(ON)}$  vs.  $V_{GS}$

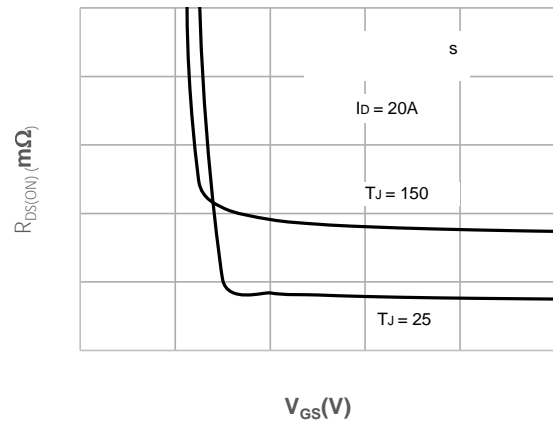
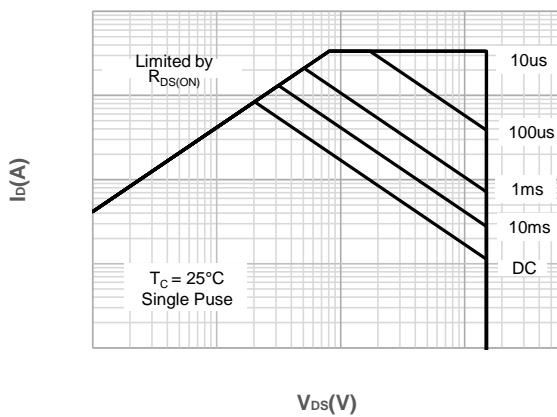
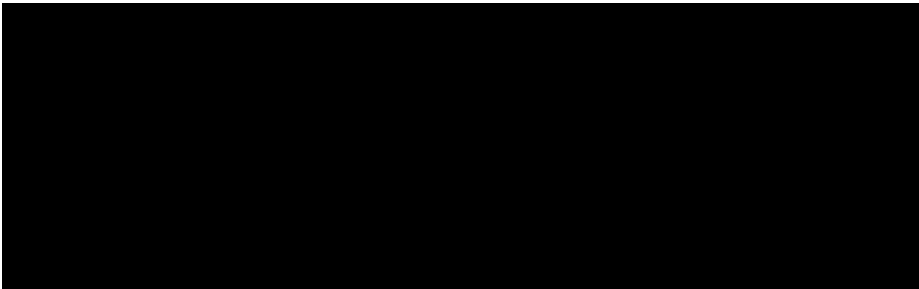


Figure 15: Maximum Safe Operating Area



**Test Circuit**



**Figure 1: Gate Charge Test Circuit & Waveform**

